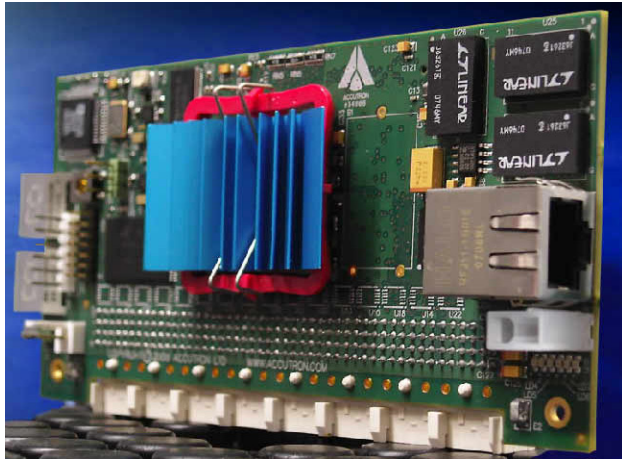




Memory Burn-in System



Type of Project
Process Improvement

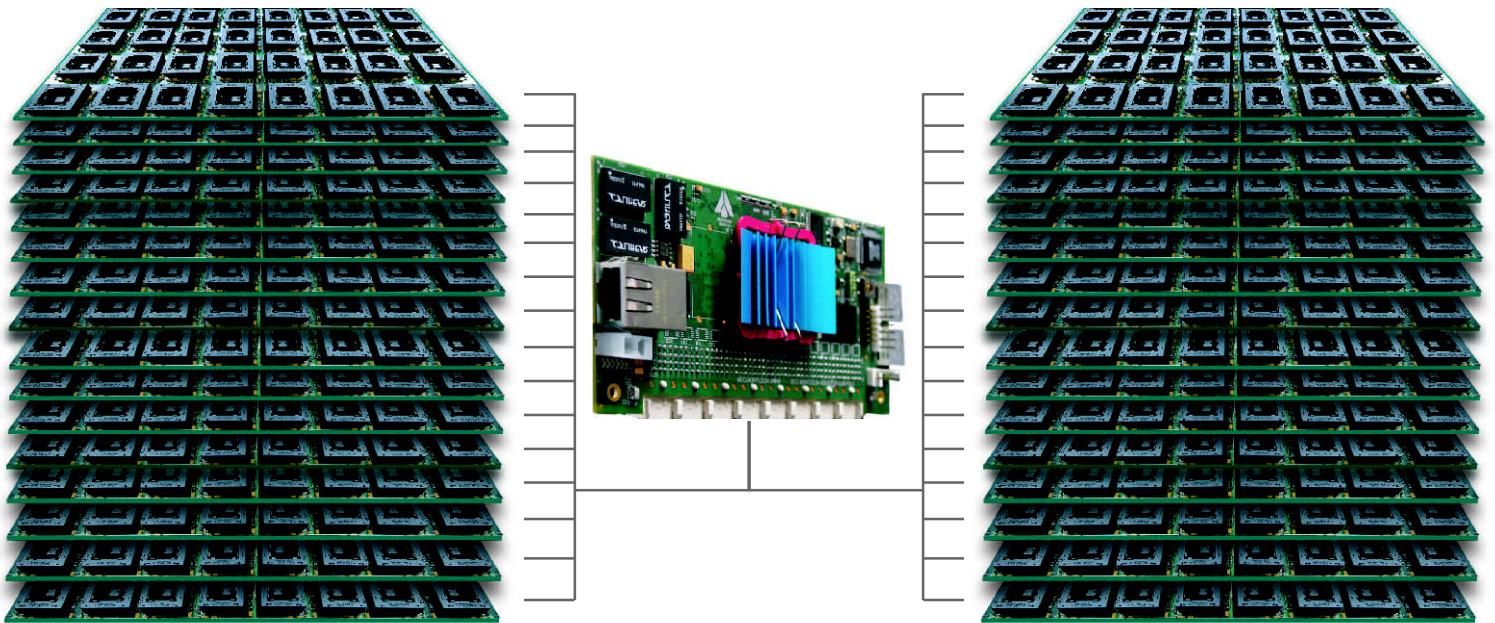
Client Brief

The cost of ATE for memory chips is becoming prohibitive. Saving cost by the testing of many devices in parallel is one solution to this challenge. The customer required a solution that could functionally test up to 1024 memory ICs in parallel.

Accutron Solution

Accutron designed a memory test solution based on FPGA technology that could test up to 32 memory chips in parallel. By connecting up to 32 of these using ethernet, the objective of testing 1024 devices simultaneously was achieved.

Testing 32 x 32 (1024!!) Memory Devices in Parallel



Skills Employed

- Concept and System Design
- Embedded CPU Design
- FPGA
- Ethernet (TCP/IP)